

Notice of References Cited	Application/Control No. 10/073,305	Applicant(s)/Patent Under Reexamination PAPIERNIAK ET AL.	
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U.S. PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	NLREG.com, Nonlinear Regression and Curve Fitting, January 18, 2002, http://web.archive.org/web/20020118073646/http://nlreg.com/
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